09/895,562

L Number	Hits	Search Text	DB	Time stamp
1	3972123	integrated circuit with dual mode test access port$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:34
2	3009849	data register$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:35
3	1243909	(integrated circuit with dual mode test access port$1) and (data register$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:36
4	2495028	intellectual property core$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:37
5	2078445	externally accessible scan path$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:37
6	431880	(intellectual property core$1) and (externally accessible scan path$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:37
7	169853	((intellectual property core$1) and (externally accessible scan path$1)) and ((integrated circuit with dual mode test access port$1) and (data register$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:40
8	46	"IEEE 1149.1 TAP"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:41
9	33	(((intellectual property core$1) and (externally accessible scan path$1)) and ((integrated circuit with dual mode test access port$1) and (data register$1))) and "IEEE 1149.1 TAP"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:42
11	5470459	enabl$3 signal$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:43
12	3709152	disabl$3 signal$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:43
13	3681902	(enabl$3 signal$1) and (disabl$3 signal$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:45

14	33	(((((intellectual property core$1) and (externally accessible scan path$1)) and ((integrated circuit with dual mode test access port$1) and (data register$1))) and "IEEE 1149.1 TAP") and ((enabl$3 signal$1) and (disabl$3 signal$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:48
15	1974031	TAP test interface	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:49
16	2214968	alternate test interface	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:49
17	1863922	(TAP test interface) and (alternate test interface)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:50
18	33	((((((intellectual property core$1) and (externally accessible scan path$1)) and ((integrated circuit with dual mode test access port$1) and (data register$1))) and "IEEE 1149.1 TAP") and ((enabl$3 signal$1) and (disabl$3 signal$1))) and ((TAP test interface) and (alternate test interface))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:50
19	3163057	scan data register$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:50
20	1123817	boundary scan register$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:50
21	684272	bypass register$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:50
22	904426	(boundary scan register$1) and (scan data register$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:52
23	542391	(bypass register$1) and ((boundary scan register$1) and (scan data register$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:52
24	881375	instruction register$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:54
25	537439	((bypass register$1) and ((boundary scan register$1) and (scan data register$1))) and (instruction register$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:55

26	24	(((bypass register$1) and ((boundary scan register$1) and (scan data register$1))) and (instruction register$1)) and ((((((intellectual property core$1) and (externally accessible scan path$1)) and ((integrated circuit with dual mode test access port$1) and (data register$1))) and "IEEE 1149.1 TAP") and ((enabl$3 signal$1) and (disabl$3 signal$1))) and ((TAP test interface) and (alternate test interface)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:55
27	5048293	first protocol	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:55
28	4740324	second protocol	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:55
29	4205536	(first protocol) and (second protocol)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:57
30	24	(((((bypass register$1) and ((boundary scan register$1) and (scan data register$1))) and (instruction register$1)) and ((((((intellectual property core$1) and (externally accessible scan path$1)) and ((integrated circuit with dual mode test access port$1) and (data register$1))) and "IEEE 1149.1 TAP") and ((enabl$3 signal$1) and (disabl$3 signal$1))) and ((TAP test interface) and (alternate test interface)))) and ((first protocol) and (second protocol))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/02/17 10:59